Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/506,081	CHIU ET AL.	
Examiner	Art Unit	
John P. Lacyk	3735	

John P. Lacyk

SEARCHED				
Class	Subclass	Date	Examiner	
600	1-8			
606	194			
604	507-510,			
	96.01,			
	97.01			
	101.01-			
	103.14	2/3/2006	JPL	

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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